

EMC TEST REPORT

For

TRAVEL CHARGER

Model Number: RG-TC-007, RG-TC-001



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Report Number : **TB-EMC083011**
Date of Test : Nov. 21-25, 2008
Date of Report : Nov. 26-27, 2008

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1. TEST RESULTS SUMMARY

Table 1 Test Results Summary

Test Items	Test Results
Conducted Disturbance	Pass
Radiated Disturbance	Pass
Harmonic Current	N/A
Flicker	Pass
ESD Immunity	Pass
Radiated Electromagnetic Field Immunity	Pass
EFT Immunity	Pass
Surge Immunity	Pass
Conducted Immunity	Pass
Voltage dips and interruptions Immunity	Pass

Remark: "N/A" means "Not applicable."

2. GENERAL INFORMATION

2.1. Report information

2.1.1. This report is not a certificate of quality; it only applies to the sample of the specific product/equipment given at the time of its testing. The results are not used to indicate or imply that they are application to the similar items. In addition, such results must not be used to indicate or imply that SMQ approves recommends or endorses the manufacture, supplier or use of such product/equipment, or that SMQ in any way guarantees the later performance of the product/equipment.

2.1.2. The sample/s mentioned in this report is/are supplied by Applicant, SMQ therefore assumes no responsibility for the accuracy of information on the brand name, model number, origin of manufacture or any information supplied.

2.1.3. Additional copies of the report are available to the Applicant at an additional fee. No third part can obtain a copy of this report through SMQ, unless the applicant has authorized SMQ in writing to do so.

2.2. Laboratory Accreditation and Relationship to Customer

The testing report were performed by the Shenzhen Academy of Metrology and Quality Inspection EMC Laboratory (Guangdong EMC compliance testing center), in their facilities located at Bldg. of Metrology & Quality Inspection, Longzhu Road, Nanshan District, Shenzhen, Guangdong, China. At the time of testing, the following bodies accredited the Laboratory:

The Laboratory is listed in the United States of American Federal Communications Commission (FCC), and the registration number is 274801.

Jun. 19, 2007 certificated by TUV Rheinland, Shenzhen (Audit Report: 02024086 004).

The certificate is valid until the next scheduled inspection or up to 24 months, at the discretion of TUV Rhineland.

2.3. Measurement Uncertainty

Available upon request.

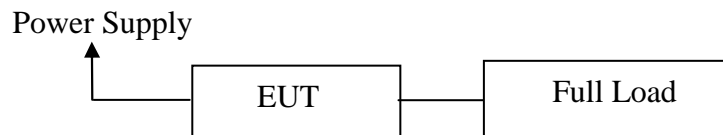
3. PRODUCT DESCRIPTION

3.1. EUT Description

Description	: TRAVEL CHARGER
Models Number	: RG-TC-007, RG-TC-001
Input	: AC100-240V, 50/60Hz, 0.15A
Output	: DC5.25V, 1A
Applicant	: ROSEN GROUPS INTERNATIONAL LIMITED
Manufacturer	: SHENZHEN ROSEN TECH CO., LTD.

Remark: All above models are identical in schematic, structure and critical components except for different model number, color and different enclosure, therefore, EMI and EMS testing was performed with RG-TC-007 only.

3.2. Block Diagram of EUT Configuration



3.3. Operating Condition of EUT

Test mode 1: Full Load

3.4. Test Conditions

Temperature: 21-23

Relative Humidity: 53~57 %

3.5. Performance Criterion

Criterion A: The equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed below a performance level specified by the manufacturer when the equipment is used as intended.

Criterion B: After the test, the equipment shall continue to operate as intended without operator intervention. No degradation of performance or loss of function is allowed, after the application of the phenomena below a performance level specified by the manufacturer, when the equipment is used as intended.

Criterion C: Loss of function is allowed, provided the function is self-recoverable, or can be restored by the operation of the controls by the user in accordance with the manufacturer's instructions.

4. TEST EQUIPMENT USED

4.1. Test Equipment Used to Measure Conducted Disturbance

Table 2 Conducted Disturbance Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB2603	EMI Test Receiver	Rohde & Schwarz	ESCS30	Jan.30, 2008	1 Year
SB2604	AMN	Rohde & Schwarz	ESH3-Z5	Jan.30, 2008	1 Year

4.2. Test Equipment Used to Measure Radiated Disturbance

Table 3 Radiated Disturbance Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB3436	EMI Test Receiver	Rohde & Schwarz	ESI26	Jan.30, 2008	1 Year
SB3440	Bilog Antenna	Chase	CBL6112B	Jan.30, 2008	1 Year

4.3. Test Equipment Used to Measure Harmonic Current /Voltage Fluctuation and Flicker

Table 4 Harmonic Current /Voltage Fluctuation and Flicker Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB2588	Harmonic flicker test system	CI	5001ix-CTS-400	Feb.21, 2008	1 Year

4.4. Test Equipment Used to Measure Electrostatic Discharge Immunity

Table 5 ESD Immunity Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB2561	ESD tester	SCHNAFFN ER	NSG435	Feb. 14, 2008	1 Year

4.5. Test Equipment Used to Measure Conducted Immunity

Table 6 Conducted Immunity Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB2605	CW sine Generator	EMTEST	CWS500	Jan.30, 2008	1 Year
SB2605/01	CDN	EMTEST	CDN-M2	Jan.30, 2008	1 Year

4.6. Test Equipment Used to Measure Radio Frequency Electromagnetic Fields Immunity

Table 7 Radiated Electromagnetic Field Immunity Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB3433	Signal Generator	Rohde & Schwarz	SMT03	Jan.30, 2008	1 Year
SB3437	Power Meter	Rohde & Schwarz	NRVD	Jan.30, 2008	1Year
SB3437/01	Voltage Probe	Rohde & Schwarz	URV5-Z2	Jan.30, 2008	1Year
SB3437/02	Voltage Probe	Rohde & Schwarz	URV5-Z2	Jan.30, 2008	1Year
SB3173	Power Amplifier	AR	150W1000	Jan.30, 2008	1Year
SB2622	Bilog Antenna	Chase	CBL6111C	Jan.30, 2008	1Year

4.7. Test Equipment Used to Measure Electrical Fast Transient/Burst Immunity

Table 8 EFT Immunity Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB3070	Simulator	EMTEST	UCS500M4	Jan. 30, 2008	1 Year

4.8. Test Equipment Used to Measure Surge Immunity

Table 9 Surge Immunity Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB3070	Simulator	EMTEST	UCS500M4	Jan. 30, 2008	1 Year

4.9. Test Equipment Used to Measure Voltage Dips and Interruptions Immunity

Table 6 Voltage Dips and Interruption Immunity Test Equipment

No.	Equipment	Manufacturer	Model No.	Last Cal.	Cal. Interval
SB2617	EMCPRO	EMTEST	----	Feb.18, 2008	1 Year

5. CONDUCTED DISTURBANCE TEST

5.1. Test Standard and Limit

5.1.1. Test Standard

EN61000-6-3:2007

5.1.2. Test Limit

Table 7 Conducted Disturbance Test Limit (Class B)

Frequency	Maximum RF Line Voltage (dB μ V)	
	Quasi-peak Level	Average Level
150kHz~500kHz	66 ~ 56 *	56 ~ 46 *
500kHz~5MHz	56	46
5MHz~30MHz	60	50

* Decreasing linearly with logarithm of the frequency

5.2. Test Procedure

The EUT is put on a table of non-conducting material that is 80cm high. The vertical conducting wall of shielding is located 40cm to the rear of the EUT. The power line of the EUT is connected to the AC mains through a Artificial Mains Network (A.M.N.). A EMI test receiver (R&S Test Receiver ESCS30) is used to test the emissions form both sides of AC line. The bandwidth of EMI test receiver is set at 9kHz.

5.3. Test Arrangement

The arrangement of the equipment is installed to meet the standards and operating in a manner, which tends to maximize its emission characteristics in a normal application. The detailed information refers to test picture.

5.4. Test Data

The emissions don't show in below are too low against the limits, the test curves are shown in the APPENDIX .

Table 8 Conducted Disturbance Test Data

Model No.: RG-TC-007									
Test Mode: 1									
Line					Neutral				
Frequency (MHz)	Quasi-Peak		Average		Frequency (MHz)	Quasi-Peak		Average	
	Reading (dBμV)	Limit (dBμV)	Reading (dBμV)	Limit (dBμV)		Reading (dBμV)	Limit (dBμV)	Reading (dBμV)	Limit (dBμV)
----	----	----	----	----	----	----	----	----	----
----	----	----	----	----	----	----	----	----	----
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6. RADIATED DISTURBANCE TEST

6.1. Test Standard and Limit

6.1.1. Test Standard

EN61000-6-3:2007

6.1.2. Test Limit

Table 9 Radiated Disturbance Test Limit (Class B)

Frequency	Limit (dB μ V/m)
	Quasi-peak Level
30MHz~230MHz	40
230MHz~1000MHz	47

* The lower limit shall apply at the transition frequency.

* The test distance is 3m.

6.2. Test Procedure

The EUT is placed on a turntable, which is 0.8 meter above ground. The turntable can rotate 360 degrees to determine the position of the maximum emission level. EUT is set **3 meters** away from the receiving antenna, which is mounted on an antenna tower. The antenna can move up and down between 1 to 4 meters to find out the maximum emission level. Broadband antenna is used as a receiving antenna. Both horizontal and vertical polarization of the antenna is set on test.

6.3. Test Arrangement

The arrangement of the equipment is installed to meet the standards and operating in a manner, which tends to maximize its emission characteristics in a normal application. The detailed information refers to test picture.

6.4. Test Data

Emissions don't show below are too low against the limits, the test curves are shown in the APPENDIX .

Table 10 Radiated Disturbance Test Data

Model No.: RG-TC-007			
Test Mode: 1			
Frequency MHz	Readings dB(μ V/m)	Polarization	Limits dB (μ V/m)
----	----	Horizontal	40
----	----	Horizontal	47
----	----	Vertical	40
----	----	Vertical	47

7. HARMONIC CURRENT EMISSION TEST

7.1. Test Standard and Limit

7.1.1. Test Standard

EN61000-3-2:2006

7.1.2. Limits

Table 11 Harmonic Current Test Limit (Class B)

Harmonic order (n)	Maximum permissible harmonic current (A)
Odd harmonics	
3	2.30
5	1.14
7	0.77
9	0.40
11	0.33
13	0.21
$15 \leq n \leq 39$	$0.15 \times 15/n$
Even harmonics	
2	1.08
4	0.43
6	0.30
$8 \leq n \leq 40$	$0.23 \times 8/n$

7.2. Test Procedure

The power cord of the EUT is connected to the output of the test system. Turn on the Power of the EUT and use the test system to test the harmonic current level.

7.3. Test Data

The active input power of this EUT is lower than 75W. Therefore, according to EN 61000-3-2, no limits are necessary.

8. VOLTAGE FLUCTUATION AND FLICKER TEST

8.1. Test Standard and Limit

8.1.1. Test Standard

EN61000-3-3:1995+A1:2001+A2:2005

8.1.2. Limit

Table 12 Flicker Test Limit

Test items	Limits
Pst	1.0
dc	3.3%
dmax	4.0%
dt	Not exceed 3.3% for 500ms

8.2. Test Procedure

The power cord of the EUT is connected to the output of the test system. Turn on the power of the EUT and use the test system to test the harmonic current level.

8.3. Test Data

Table 13 Flicker test Data

Model No.: RG-TC-007		
Test Mode: 1		
Items	Reading	Limit
Dmax	0.00	4.0%
Dc	0.00	3.3%
Dt	0.00	Not exceed 3.3% for 500ms
Pst	0.005	1.0

9. ELECTROSTATIC DISCHARGE IMMUNITY TEST

9.1. Test Requirements

9.1.1. Test Standard

EN61000-6-1:2007 (EN61000-4-2:1995+A1:1998+A2:2002)

9.1.2. Test Level

Table 14 Test Level for ESD

Port	Test Specification
Enclosure Port	8kV air discharge 4kV contact discharge

9.1.3. Performance criterion: **B**

9.2. Test Procedure

9.2.1. Contact Discharge:

The ESD generator is held perpendicular to the surface to which the discharge is applied and the tip of the discharge electrode touch the surface of EUT. Then turn the discharge switch. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

9.2.2. Air Discharge:

Air discharge is used where contact discharge can't be applied. The round discharge tip of the discharge electrode shall be approached as fast as possible to touch the EUT. After each discharge, the discharge electrode shall be removed from the EUT. The generator is then re-triggered for a new single discharge and repeated 10 times for each pre-selected test point. This procedure shall be repeated until all the air discharge completed.

9.2.3. Indirect discharge for horizontal coupling plane

At least 10 single discharges shall be applied to the horizontal coupling plane, at points on each side of the EUT.

9.2.4. Indirect discharge for vertical coupling plane

At least 10 single discharge shall be applied to the center of one vertical edge of the coupling plane. The coupling plane, of dimensions 0.5m X 0.5m, is placed parallel to, and positioned at a distance of 0.1m from the EUT. Discharges shall be applied to the coupling plane, with this plane in sufficient different positions that the four faces of the EUT are completely illuminated.

9.3. Test Data

Table 15 ESD Test Data

Model No.: RG-TC-007				
Test Mode: 1				
Location	Voltage	Amount of test points	Discharge Method	Results
Nonconductive Enclosure	± 8kV	4	A	Pass
HCP	± 4kV	4	C	Pass
VCP	± 4kV	4	C	Pass
Screw	± 4kV	4	C	Pass

10. RADIATED ELECTROMAGNETIC FIELD IMMUNITY TEST

10.1. Test Requirements

10.1.1. Test Standard

EN61000-6-1:2007 (EN61000-4-3:2006)

10.1.2. Test Level

Table 16 Test Level for Radiated Electromagnetic Field Immunity Test

Port	Test Specification
Enclosure Port	80-1000MHz 3 V/m 80 % AM(1kHz)

10.1.3. Performance criterion: A

10.2. Test Procedure

The EUT and its simulators are placed on a turn table which is 0.8 meter above ground. EUT is set 3 meter away from the transmitting antenna which is mounted on an antenna tower. Both horizontal and vertical polarization of the antenna are set on Test. Each of the four sides of EUT must be faced this transmitting antenna and measured individually. In order to judge the EUT performance, a CCD camera is used to monitor EUT screen.

10.3. Test Data

Table 17 Radiated Electromagnetic Field Immunity Test Data

Model No.: RG-TC-007		
Test Mode: 1		
Frequency Rang (MHz)	80-1000 MHz	
Field Strength (V/m)	3V/m	
Steps (%)	1%	
	Horizontal	Vertical
Front	Pass	Pass
Rear	Pass	Pass
Left	Pass	Pass
Right	Pass	Pass

11. ELECTRICAL FAST TRANSIENT/BURST TEST

11.1. Test Requirements

11.1.1. Test Standard

EN61000-6-1:2007 (EN61000-4-4:2004)

11.1.2. Level

Table 18 Test Level for EFT

Port	Test Specification
Input and output AC power Port	1kV 5/50 ns Tr/Th 5kHz repetition frequency

11.1.3. Performance criterion : **B**

11.2. Test Procedure

11.2.1. For input and output AC power ports:

The EUT is connected to the power mains by using a coupling device which couples the EFT interference signal to AC power lines. Both polarities of the test voltage should be applied during compliance test and the duration of the test is 1 minute.

11.2.2. For signal lines and control lines ports:

A coupling clamp is use to couple the EFT interference signal to the signal and control lines. Both polarities of the test voltage should be applied during compliance test and the duration of the test is 1 minute.

11.2.3. For DC input and DC output power ports:

The EUT is connected to the power mains by using a coupling device which couples the EFT interference signal to AC power lines. Both polarities of the test voltage should be applied during compliance test and the duration of the test is 1 minute.

11.3. Test Data

Table 19 EFT Test Data

Model No.: RG-TC-007				
Test Mode: 1				
Injected Line	Voltage (kV)	Test Time (s)	Injected Method	Result
L	+1	30	Direct	Pass
	-1	30	Direct	Pass
N	+1	30	Direct	Pass
	-1	30	Direct	Pass
L,N	+1	30	Direct	Pass
	-1	30	Direct	Pass

12. SURGE IMMUNITY TEST

12.1. Test Requirements

12.1.1. Test Standard

EN61000-6-1:2007 (EN61000-4-5:2006)

12.1.2. Level

Table 20 Test Level for Surge

Port	Test Specification
Input AC power Port	1.2/50(8/20) μ s Tr/Th 1kV L-N 2kV L-PE, N-PE

12.1.3. Performance criterion : B

12.2. Test Procedure

Set up the EUT and test generator as shown above. A coupling device is used to couple the surge signal to the EUT. Five positive and five negative pulses is applicable and the duration of the test is 1 minutes.

12.3. Test Data

Table 21 Surge Test Data

Model No.: RG-TC-007						
Test Mode: 1						
Injected Line	Wave Form	Voltage (kV)	Phase	Number of Pulse	Interval time	Result
L-N	1.2/50 μ s	+1	0 ° ,90 ° ,270 °	30	60s	Pass
		-1	0 ° ,90 ° ,270 °	30	60s	Pass

13. CONDUCTED IMMUNITY TEST

13.1. Test Requirements

13.1.1. Test Standard

EN61000-6-1:2007 (EN61000-4-6:1996+A1:2001)

13.1.2. Level

Table 22 Test Level for Conducted Immunity

Port	Test Specification
Input and output AC power port	0.15MHz~80MHz 3V(r.m.s.) (unmodulated)

13.1.3. Performance criterion: A

13.2. Test Procedure

Set up the EUT, CDN and test generators as shown above. The test is performed with the generator contacted to each CDN in turn. The frequency range is swept from 150kHz to 80MHz, using the signal levels established during the setting process, and with the disturbance signal 80% amplitude modulated with a 1kHz sine wave.

13.3. Test Data

Table 23 Conducted Immunity Test Data

Model No.: RG-TC-007			
Test Mode: 1			
Frequency Range (MHz)	Injected Position	Strength	Result
0.15MHz ~ 80MHz	AC Lines	3V(rms), Unmodulated	Pass
80MHz ~ 230MHz	AC Lines	3V(rms), Unmodulated	Pass
Dwell time: 0.3s; Steps: 1%			

14. VOLTAGE DIPS AND INTERRUPTIONS IMMUNITY TEST

14.1. Test Requirements

14.1.1. Test Standard

EN61000-6-1:2007 (EN61000-4-11:2004)

14.1.2. Level

Table 24 Test Level for Voltage Dips and Interruptions

Port	Environmental phenomenon	Voltage dip and short interruptions % U _T	Duration
Input AC power port	Voltage dips	>95	10ms
		30	500ms
	Voltage interruptions	>95	5000ms

14.1.3. Performance criterion : >95% reduction **C(dips)**

30% reduction **B(dips)**

>95% reduction **C(interruptions)**

14.2. Test Procedure

Set up the EUT and test generator as shown above. The EUT is tested for each selected combination of test level and duration with a sequence of three dips/interruptions with intervals of 10s minimum.

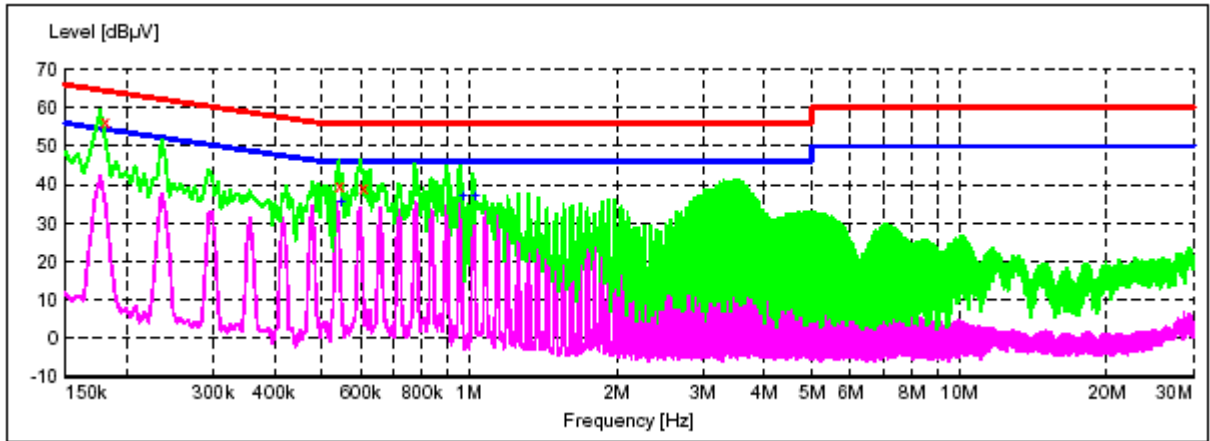
14.3. Test Data

Table 25 Voltage Dips and Interruptions Test Data

Model No.: RG-TC-007				
Test Mode: 1				
Environmental phenomenon	Voltage Dips & Short Interruptions % U_T	Duration (ms)	Phase Angle	Result
Voltage dips	>95	10	0°	Pass
	30	500	0°	Pass
Voltage interruptions	>95	5000	0°	Pass

APPENDIX I TEST CURVES

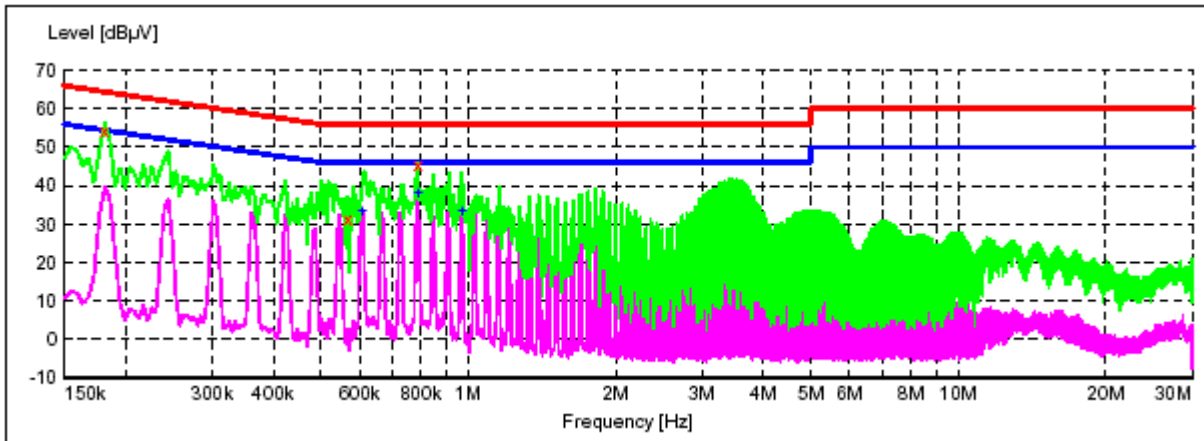
Conducted Disturbance
EUT: TRAVEL CHARGER
M/N: RG-TC-007
Operating Condition: Full Load
Test Specification: L
Comment: AC230V/50Hz



Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.181500	56.50	11.0	64	7.9	QP	L1	GND
0.546000	39.70	10.2	56	16.3	QP	L1	GND
0.609000	38.90	10.2	56	17.1	QP	L1	GND

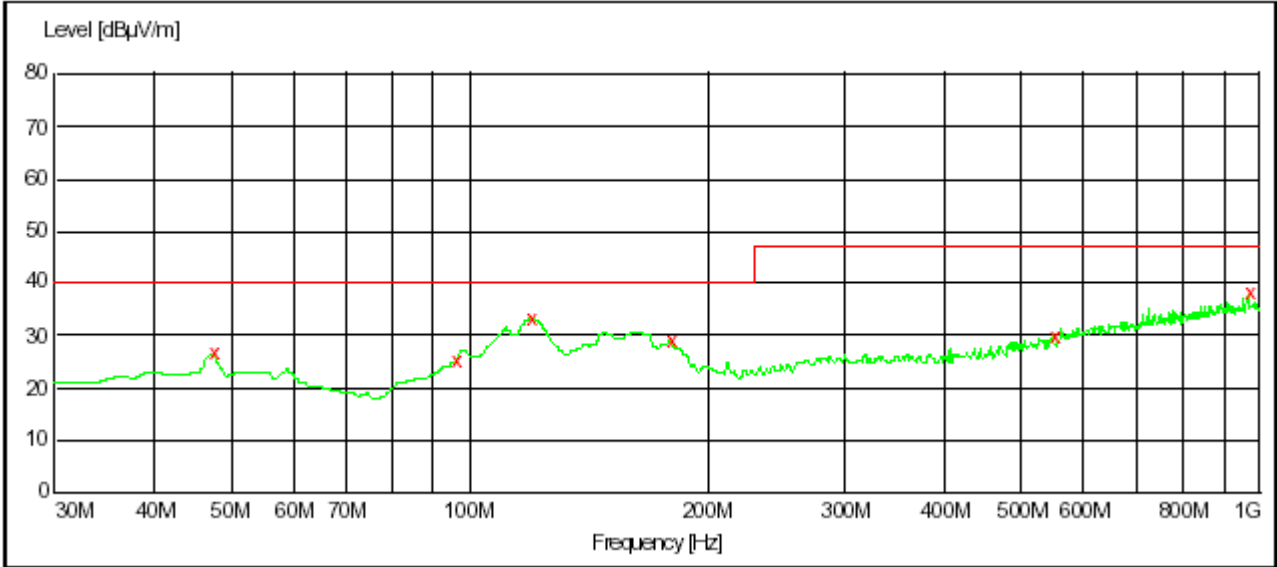
Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.546000	35.70	10.2	46	10.3	AV	L1	GND
0.969000	37.10	10.3	46	8.9	AV	L1	GND
1.032000	37.10	10.3	46	8.9	AV	L1	GND

Conducted Disturbance
EUT: TRAVEL CHARGER
M/N: RG-TC-007
Operating Condition: Full Load
Test Specification: N
Comment: AC230V/50Hz



Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.181500	54.40	11.0	64	10.0	QP	N	GND
0.568500	31.30	10.2	56	24.7	QP	N	GND
0.789000	45.50	10.2	56	10.5	QP	N	GND
Frequency MHz	Level dBµV	Transd dB	Limit dBµV	Margin dB	Detector	Line	PE
0.609000	33.60	10.2	46	12.4	AV	N	GND
0.789000	38.10	10.2	46	7.9	AV	N	GND
0.973500	33.30	10.3	46	12.7	AV	N	GND

Radiated Disturbance
EN 55022B
EUT: TRAVEL CHARGER **M/N: RG-TC-007**
Operating Condition: Full Load
Test Site: SMQ EMC Lab. SAC
Test Specification: Horizontal
Comment: AC230V, 50Hz



Radiated Disturbance

EN 55022B

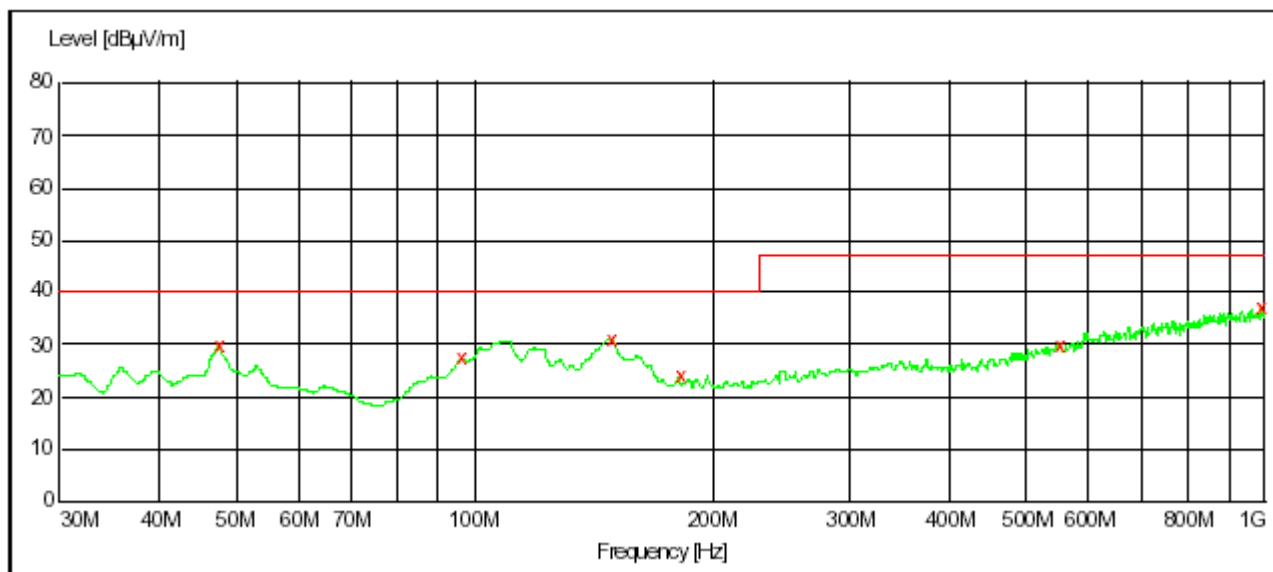
EUT: TRAVEL CHARGER M/N: RG-TC-007

Operating Condition: Full Load

Test Site: SMQ EMC Lab. SAC

Test Specification: Vertical

Comment: AC230V, 50Hz



APPENDIX II TEST PICTURES

Photo 1 Appearance of EUT



Photo 2 Appearance of EUT



Photo 3 Inside of EUT

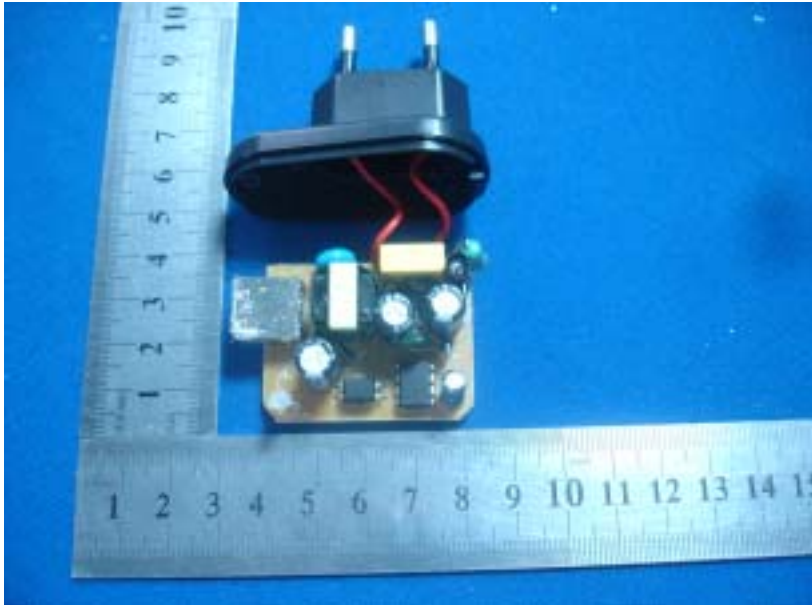


Photo 4 Appearance of PCB

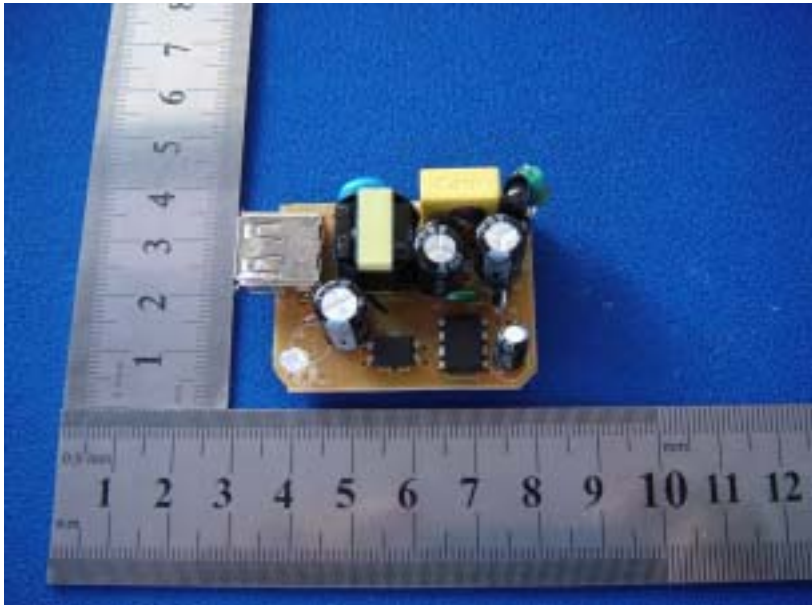


Photo 5 Appearance of PCB

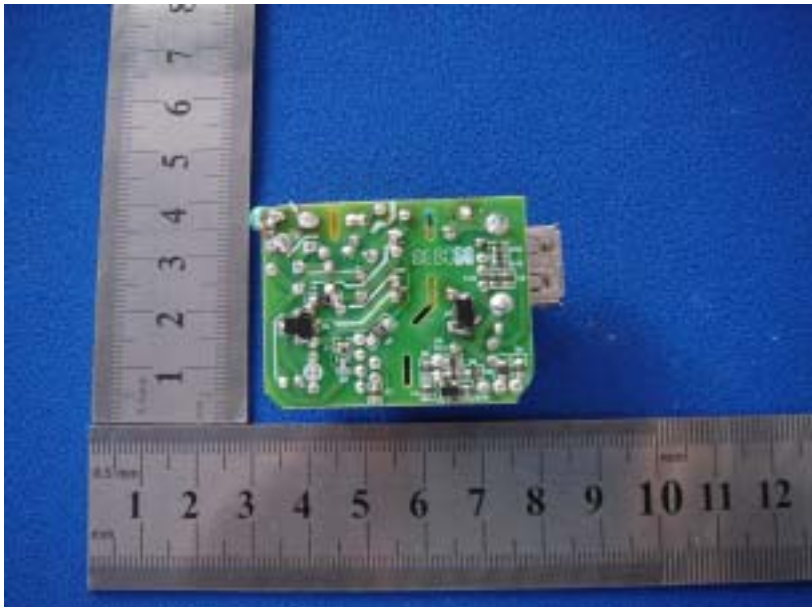


Photo 6 Conducted Disturbance Test



Photo 7 Radiated Disturbance Test



Photo 8 ESD Immunity Test

